Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/790,733	CHEN ET AL.	
Examiner	Art Unit	
Anh Q. Tran	2819	

SEARCHED			
Class	Subclass	Date	Examiner
326	56 1 58	76/05	AT
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	80 81		
			

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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